Se	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/605,654	HO, HENG-CHUN	
Examiner	Art Unit	
Anabel M. Ton	2875	

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Class	Subclass	Date	Examiner
40	546,547	11/10/2005	AT
362	602,604		
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